

Notice of References Cited	Application/Control No. 10/517,257		Applicant(s)/Patent Under Reexamination HAQ ET AL.	
	Examiner ROBERT VETERE		Art Unit 1792	Page 1 of 1

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*	B	US-5,780,101	07-1998	Nolan et al.	427/216
*	C	US-7,014,737	03-2006	Harutyunyan et al.	204/158.2
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.